

**Notice of References Cited**

Application/Control No.

09/842,948

Applicant(s)/Patent Under  
Reexamination  
PETRY ET AL.

Examiner

PHILIP WANG

Art Unit

2191

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,931,602 B1	08-2005	Silver et al.	715/771
*	B	US-6,813,621	11-2004	Taylor et al.	707/102
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	Comaniciu, "Image-guided decision support system for pathology", Springer-Verlag 2000, Machine Vision and Application, pp. 213-224

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.